

Search Notes



Application/Control No.

10/501,744

Examiner

Sang Y. Paik

Applicant(s)/Patent under Reexamination

KACHI ET AL.

Art Unit

3742

SEARCHED

Class	Subclass	Date	Examiner
219	443.1 444.1 390		
392	418		
118	124		
	725	7/24/05	SP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EPST TGA SEARCHED	8/24/05	X